

**RESPONSE UNDER 37 C.F.R. § 1.116**  
**RECEIVED**  
**CENTRAL FAX CENTER**  
**EXPEDITED PROCEDURE**  
**EXAMINING GROUP 2877**

OCT 04 2004

**PATENT**  
**5589-02305/P688-05**

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re Application of:  
 Nikoonahad et al.

Serial No. 09/957,468

Filed: September 20, 2001

For: **METHODS AND SYSTEMS FOR  
 DETERMINING A CRITICAL  
 DIMENSION, A PRESENCE OF  
 DEFECTS, AND A THIN FILM  
 CHARACTERISTIC OF A SPECIMEN**

§ Group Art Unit: 2877  
 § Examiner: Pham, H.

§ Atty. Dkt. No. 5589-02305

§ I hereby certify that this correspondence is being  
 § transmitted via facsimile or deposited with the U.S. Postal  
 § Service as First Class Mail in an envelope addressed to: Mail  
 § Stop AF, Commissioner for Patents, P.O. Box 1450, Alexandria,  
 § VA 22313-1450, on the date indicated below:

10-1-04  
 Date

Pamela Gerik  
 Pamela Gerik

**RESPONSE AFTER FINAL REJECTION PURSUANT TO 37 C.F.R. § 1.116**

OK TO ENTER  
 AP  
 10/15/04  
 Mail Stop AF  
 Commissioner for Patents  
 P.O. Box 1450  
 Alexandria, VA 22313-1450

Dear Sir/ Madam:

This paper is submitted in response to the Final Office Action mailed August 3, 2004, to further highlight reasons why the application is in condition for allowance. Applicant submits the present paper complies with the requirements of 37 C.F.R. § 1.116.

Remarks begin on page 2 of this paper.

Received 10/04/04 in CFC